

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	(716/21).ccls. and (systematic adj defect\$2) and (circuit adj layout) and ( feature adj vector\$2) and (index adj process\$3) and (defect adj region\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:16
L2	0	(716/19).ccls. and (systematic adj defect\$2) and (circuit adj layout) and ( feature adj vector\$2) and (index adj process\$3) and (defect adj region\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:16
L3	0	(716/4).ccls. and (systematic adj defect\$2) and (circuit adj layout) and ( feature adj vector\$2) and (index adj process\$3) and (defect adj region\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:16
L4	0	(716/5).ccls. and (systematic adj defect\$2) and (circuit adj layout) and ( feature adj vector\$2) and (index adj process\$3) and (defect adj region\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:16
L5	0	("716"/\$).ccls. and (systematic adj defect\$2) and (circuit adj layout) and ( feature adj vector\$2) and (index adj process\$3) and (defect adj region\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:16
L6	1	(382/145).ccls. and (systematic adj defect\$2) and (circuit adj layout) and ( feature adj vector\$2) and (index adj process\$3) and (defect adj region\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:17
L7	2	(systematic adj defect\$2) and (circuit adj layout) and ( feature adj vector\$2) and (index adj process\$3) and (defect adj region\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:18
L8	1	((systematic adj defect\$2) and (circuit adj layout) and ( feature adj vector\$2) and (index adj process\$3) and (defect adj region\$2)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:18
L9	2	(systematic adj defect\$2) and (circuit adj layout) and ( feature adj vector\$2) and (index adj process\$3) and (defect adj (region\$2 or area\$2 or zone\$2))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:47

## EAST Search History

L10	0	(systematic adj defect\$2) and (circuit adj design) and (feature adj vector\$2) and (defeat adj vector\$2) and (index adj process\$3) and (defect adj (region\$2 or area\$2 or zone\$2)) and (bas\$3 adj pattern\$2) and (window adj grid)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:42
L11	0	(systematic adj defect\$2) and (circuit adj layout) and (feature adj vector\$2) and (defeat adj vector\$2) and (index adj process\$3) and (defect adj (region\$2 or area\$2 or zone\$2)) and (bas\$3 adj pattern\$2) and (window adj grid)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:45
L12	0	(systematic adj defect\$2) and (circuit adj design) and (feature adj vector\$2) and (defeat adj vector\$2) and (index adj process\$3) and (defect adj (region\$2 or area\$2 or zone\$2)) and (basis adj pattern\$2) and (window adj grid)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:46
L13	2	(systematic adj defect\$2) and (circuit adj design) and ( feature adj vector\$2) and (index adj process\$3) and (defect adj (region\$2 or area\$2 or zone\$2))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:47
L14	1	(systematic adj defect\$2) and (circuit adj design) and ( feature adj vector\$2) and (index adj process\$3) and (defect adj (region\$2 or area\$2 or zone\$2)) and (window adj grid)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:49
L15	1	((systematic adj defect\$2) and (circuit adj design) and ( feature adj vector\$2) and (index adj process\$3) and (defect adj (region\$2 or area\$2 or zone\$2)) and (window adj grid)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:49
S1	1126	716/21	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:11
S2	1524	716/19	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 10:35

## EAST Search History

S3	3468	716/4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 10:35
S4	2590	716/5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 10:35

[Web](#) [Images](#) [Video](#) [News](#) [Maps](#) [Gmail](#) [more ▾](#)

[Sign in](#)

Google

("systematic defects")("circuit layout")("basis p

Search

[Advanced Search](#)  
[Preferences](#)

Web

Did you mean: ("systematic defects")("circuit layout")(**basic** patterns")("feature vectors")("defeat vector")

No standard web pages containing all your search terms were found.

Your search - ("**systematic defects**")("circuit layout")("basis patterns")("feature vectors")("defeat vector") - did not match any documents.

Suggestions:

- Make sure all words are spelled correctly.
- Try different keywords.
- Try more general keywords.
- Try fewer keywords.

©2007 Google - [Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

[Web](#) [Images](#) [Video](#) [News](#) [Maps](#) [Gmail](#) [more ▾](#)

[Sign in](#)

[Google](#)

("systematic defects")("circuit layout")(patterns

[Advanced Search](#)  
[Preferences](#)

**Web**

---

Tip: Try removing quotes from your search to get more results.

Your search - ("**systematic defects**")("**circuit layout**")(**patterns**)("**feature vectors**")("**defeat vectors**") - did not match any documents.

Suggestions:

- Make sure all words are spelled correctly.
- Try different keywords.
- Try more general keywords.
- Try fewer keywords.

©2007 Google - [Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

---

[Web](#) [Images](#) [Video](#) [News](#) [Maps](#) [Gmail](#) [more ▾](#)

[Sign in](#)

Google

("circuit layout")(patterns)("feature vectors")("d

Search

[Advanced Search](#)  
[Preferences](#)

Web

Tip: Try removing quotes from your search to get more results.

Your search - ("**circuit layout**")(**patterns**)("**feature vectors**")("**defeat vectors**") "**locating systematic defects**" - did not match any documents.

Suggestions:

- Make sure all words are spelled correctly.
- Try different keywords.
- Try more general keywords.
- Try fewer keywords.

©2007 Google - [Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

[Web](#) [Images](#) [Video](#) [News](#) [Maps](#) [Gmail](#) [more ▾](#)

[Sign in](#)

Google

(circuit)(shapes)(layout)("feature vectors") "loc

Search

[Advanced Search](#)  
[Preferences](#)

**Web** Results 1 - 1 of 1 for **(circuit)(shapes)(layout)("feature vectors") "locating systematic defects". (0.1**

Tip: Try removing quotes from your search to get more results.

**SYSTEM FOR SEARCH AND ANALYSIS OF SYSTEMATIC DEFECTS IN INTEGRATED ...**

Disclosed is a method of **locating systematic defects** in integrated circuits. ... comprising:  
transforming **shapes** in a **circuit layout** into **feature vectors**; ...

[www.freepatentsonline.com/20050094863.html](http://www.freepatentsonline.com/20050094863.html) - 47k - [Cached](#) - [Similar pages](#)

Download [Google Pack](#): free essential software for your PC

(circuit)(shapes)(layout)("feature vec

Search

[Search within results](#) | [Language Tools](#) | [Search Tips](#) | [Dissatisfied? Help us improve](#)

©2007 Google - [Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

Google

("systematic defects")(circuit)(shapes)(layout)(

# Search

## Advanced Search Preferences

Web Results 1 - 1 of 1 for ("systematic defects")(circuit)(shapes)(layout)("feature vectors")(window)(gri

**Tip:** Try removing quotes from your search to get more results.

# SYSTEM FOR SEARCH AND ANALYSIS OF SYSTEMATIC DEFECTS IN INTEGRATED ...

The invention transforms **shapes** in a each **window** into **feature vectors** by ... and said **shapes** in said **circuit layout**; and comparing said **feature vectors** to ...

www.freepatentsonline.com/20050094863.html - 47k - Cached - Similar pages

Download Google Pack: free essential software for your PC

("systematic defects")(circuit)(shape

# Search

[Search within results](#) | [Language Tools](#) | [Search Tips](#) | [Dissatisfied? Help us improve](#)

©2007 Google - [Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)





Welcome United States Patent and Trademark Office

[Search Results](#)[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)

Results for "(((circuit layout) &lt;and&gt; (systematic defects) &lt;and&gt; (feature vectors) &lt;and&gt; (index...)"

e-mail

Your search matched **0** documents.A maximum of **100** results are displayed, **25** to a page, sorted by **Relevance** in **Descending** order.

## » Search Options

[View Session History](#)[New Search](#)

## Modify Search

(((circuit layout) &lt;and&gt; (systematic defects) &lt;and&gt; (feature vectors) &lt;and&gt; (index))&lt;

☐ Check to search only within this results setDisplay Format: ☒ Citation ☐ Citation & Abstract

## » Key

IEEE JNL IEEE Journal or Magazine

IET JNL IET Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IET CNF IET Conference Proceeding

IEEE STD IEEE Standard

**No results were found.**

Please edit your search criteria and try again. Refer to the Help pages if you need assistance.

Indexed by  
[Help](#) [Contact Us](#) [Privacy &](#)

© Copyright 2006 IEEE –